

RELIABILITY MONITOR

DS1000M-100 JAN '99 MONITOR-HYUNDAI,CHINA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1000	E3	9847	DH833179ADA	8	DIP	300	CPS China
PROCESS Single Poly, Single Metal 1.2 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23057	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
23178	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:				FAIL RATE (Fits): 30
23179	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				
23180	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				
23181	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1232L APR '99 MONITOR-CHIPAC,KOREA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232L	C2	9848	DL829603AAC	8	SOIC	150	CPK Korea
PROCESS Single Poly, Single Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24189	INFANT LIFE	125C, 7.0 VOLTS	230	48	HOUR	0
24190	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
TOTAL:			71	DEVICE HRS: 1.29E+07		0
23660	ULTRASOUND	J-STD-020	0	1	DAYS	
TOTAL:						
23661	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	144	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
24191	TEMP CYCLE	-55C TO 125C	39	300	CYCL	0
			39	1000	CYCL	
TOTAL:						0
24192	HAST	130C, 85%R.H.,5.5V	77	100	HOUR	
TOTAL:						
24193	AUTOCLAVE	121C STEAM, UNBIASED	36	96	HOUR	
TOTAL:						

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1233Z-10 APR '99 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	9911	DM837033ABA	3	SOT223	140	Carsem
PROCESS Single Poly, Single Metal 1.2 μm Zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: Tuse:
Ea: Vuse:
β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23773	INFANT LIFE	125C, 7.0 VOLTS	229	48	HOUR	0
23939	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
TOTAL:			30	DEVICE HRS: 3.07E+07		0
23662	ULTRASOUND	J-STD-020	0	1	DAYS	
	EXTERNAL VISUAL	MIL-STD-883-2009	0	1	DAYS	
TOTAL:						
23663	STORAGE LIFE	125C	233	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	233	192	HOUR	
	CONVECTION REFLOW	235C	233	195	PASS	0
TOTAL:						0
23772	PRECONDITION U/S	J-STD-020	0	2	DAYS	
TOTAL:						
23940	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
23941	HAST	130C, 85%R.H.,5.5V	72	100	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1233Z-10 APR '99 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	9911	DM837033ABA	3	SOT223	140	Carsem
PROCESS Single Poly, Single Metal 1.2 μm Zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23942	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1267-010 FEB '99 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	9823	DK807766AAH	20	TSSOP	170	Anam, PI (ATP)
PROCESS Single Poly, Single Metal 1.2 µm Poly1 Resistor							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24044	INFANT LIFE	125C, 6.0 V, -4.0V	227	48	HOUR	2
24132	HIGH VOLTAGE LIFE	125C, 6.0 V, -4.0V	77	336	HOUR	0
		125C, 6.0 V, -4.0V	77	664	HOUR	
TOTAL:			275	DEVICE HRS: 1.13E+07		2
23262	ULTRASOUND	J-STD-020	0	1	DAYS	
TOTAL:						
23263	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	
TOTAL:						
24043	PRECONDITION U/S	J-STD-020	0	2	DAYS	
TOTAL:						
24133	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	700	CYCL	
TOTAL:						0
24134	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	
TOTAL:						
24135	AUTOCLAVE	121C STEAM, UNBIASED	33	96	HOUR	

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1267-010 FEB '99 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	9823	DK807766AAH	20	TSSOP	170	Anam, PI (ATP)
PROCESS Single Poly, Single Metal 1.2 μm Poly1 Resistor							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
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TOTAL:

JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION
24044	CONTINUITY	IN VERIFICATION	NA

Empty "No of Fails" TOTAL implies that Material is still in stess

RELIABILITY MONITOR

DS1267 NOV '98 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	9823	DK803107AAE	20	TSSOP	170	Anam, PI (ATP)
PROCESS Single Poly, Single Metal 1.2 μm Poly1 Resistor							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23026	INFANT LIFE	125C, 6.0 V, -4.0V	230	48	HOUR	0
23159	HIGH VOLTAGE LIFE	125C, 6.0 V, -4.0V	77	336	HOUR	0
		125C, 6.0 V, -4.0V	77	1000	HOUR	0
TOTAL:			81	DEVICE HRS: 1.13E+07		0
22790	ULTRASOUND	J-STD-020	3	1	DAYS	0
TOTAL:						0
22791	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	SOLDER HEAT	HTC VAPOR PHASE	237	3	PASS	0
TOTAL:						0
23025	PRECONDITION U/S	J-STD-020	4	1	DAYS	0
TOTAL:						0
23160	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
23161	BIASED MOISTURE	85/85, 5.5 VOLTS	76	274	HOUR	0
			76	959	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1267 NOV '98 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	9823	DK803107AAE	20	TSSOP	170	Anam, PI (ATP)
PROCESS Single Poly, Single Metal 1.2 μ m Poly1 Resistor							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23162	AUTOCLAVE	121C STEAM, UNBIASED	37	96	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stess

RELIABILITY MONITOR

DS1302 MAR '99 MONITOR - ANAM-PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1302	A3	9838	DK818104ADA	8	DIP	300	Anam, PI (ATP)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23359	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	
TOTAL:			FAIL RATE (Fits):		DEVICE HRS: 1.44E+06	

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1302 JUN '99 MONITOR-ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1302	A3	9905	DK824165AAA	8	DIP	300	Anam, PI (ATP)

PROCESS Single Poly, Double Metal 0.8 μm Standard Process

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23938	INFANT LIFE	125C, 6.0 VOLTS	230	48	HOUR	0
TOTAL:			FAIL RATE (Fits): 646	DEVICE HRS: 1.42E+06		0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1621S JUN '99 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1621	A7	9915	DK815282AAB	8	SOIC	150	Anam, PI (ATP)
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24321	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
TOTAL:			233	FAIL RATE (Fits): DEVICE HRS: 3.92E+06		0
24315	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	241	168	HOUR	
	CONVECTION REFLOW	235C	241	3	PASS	0
TOTAL:						0
24325	WRITE CYCLE STRESS	+85C, 7.0 VOLTS	47	50	KCYC	
TOTAL:						

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1803-010 NOV '98 MONITOR - HYUNDAI,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9833	DL820412AAB	16	SOIC	150	CPK Korea
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23173	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
23923	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
TOTAL:			30	DEVICE HRS: 3.08E+07		0
22797	ULTRASOUND	J-STD-020	4	1	DAYS	0
TOTAL:						0
22798	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
23172	PRECONDITION U/S	J-STD-020	4	1	DAYS	0
TOTAL:						0
23924	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
23925	BIASED MOISTURE	85/85, 5.5 VOLTS	0	274	HOUR	0
TOTAL:						0
23926	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1803-010 FEB '99 MONITOR - HYUNDAI,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9835	DL818111AAB	16	SOIC	150	CPK Korea
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23928	INFANT LIFE	125C, 7.0 VOLTS	232	48	HOUR	0
24003	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	76	336	HOUR	1
		125C, 7.0 VOLTS	76	1000	HOUR	
TOTAL:			66	DEVICE HRS: 3.04E+07		1
23274	ULTRASOUND	J-STD-020	0	1	DAYS	
TOTAL:						
23275	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
23927	PRECONDITION U/S	J-STD-020	0	2	DAYS	
TOTAL:						
24004	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	
TOTAL:						0
24005	BIASED MOISTURE	85/85, 5.5 VOLTS	0	274	HOUR	
TOTAL:						
24006	AUTOCLAVE	121C STEAM, UNBIASED	36	96	HOUR	2

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1803-010 FEB '99 MONITOR - HYUNDAI,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9835	DL818111AAB	16	SOIC	150	CPK Korea
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						2
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24003	W1PUP3V	IN PROCESS	IN PROCESS			
24006	CONTINUITY	IN PROCESS	IN PROCESS			

Empty "No of Fails" TOTAL implies that Material is still in stess

RELIABILITY MONITOR

DS1869 DEC '98 MONITOR-NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1869	A3	9829	DJ821533ABB	8	SOIC	208	NSEB
PROCESS Single Poly, Single Metal 1.2 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23024	INFANT LIFE	125C, 7.0 VOLTS	236	48	HOUR	
TOTAL:			FAIL RATE (Fits):		DEVICE HRS: 3.96E+06	
22899	ULTRASOUND	J-STD-020	4	1	DAYS	0
TOTAL:			0			
22900	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	240	3	PASS	0
TOTAL:			0			
23023	PRECONDITION U/S	J-STD-020	4	1	DAYS	0
TOTAL:			0			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1869S MAR '99 MONITOR - NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1869	A3	9829	DJ821534ABB	8	SOIC	208	NSEB
PROCESS Single Poly, Single Metal 1.2 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: Tuse:
Ea: Vuse:
β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23440	INFANT LIFE	125C, 7.0 VOLTS	237	48	HOUR	0
24022	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	76	336	HOUR	1
		125C, 7.0 VOLTS	76	1000	HOUR	
		TOTAL:			FAIL RATE (Fits): 66 DEVICE HRS: 3.05E+07	1
23360	ULTRASOUND	J-STD-020	4	1	DAYS	0
		TOTAL:				0
23361	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
		TOTAL:				0
23439	PRECONDITION U/S	J-STD-020	4	1	DAYS	0
		TOTAL:				0
24023	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	
		TOTAL:				0
24024	BIASED MOISTURE	85/85, 5.5 VOLTS	0	274	HOUR	
		TOTAL:				
24025	WRITE CYCLE STRESS	+85C, 7.0 VOLTS	50	25	KCYC	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1869S MAR '99 MONITOR - NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1869	A3	9829	DJ821534ABB	8	SOIC	208	NSEB
PROCESS Single Poly, Single Metal 1.2 μ m E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β :

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0
24288	STORAGE LIFE	150C	50	336	HOUR	

JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION
24022	ABS LINEARITY	IN VERIFICATION	NA

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1869 JUN '99 MONITOR - NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1869	A3	9836	DJ824252AAC	8	SOIC	208	NSEB
PROCESS Single Poly, Single Metal 1.2 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: Tuse:
Ea: Vuse:
β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24032	INFANT LIFE	125C, 7.0 VOLTS	230	48	HOUR	0
24228	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	70	336	HOUR	
TOTAL:			76	DEVICE HRS: 1.21E+07		0
23944	ULTRASOUND	J-STD-020	0	2	DAYS	
TOTAL:						
23945	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	234	3	PASS	7
TOTAL:						7
24031	PRECONDITION U/S	J-STD-020	0	2	DAYS	
TOTAL:						
24229	TEMP CYCLE	-55C TO 125C	39	300	CYCL	0
TOTAL:						0
24231	WRITE CYCLE STRESS	+85C, 7.0 VOLTS	50	25	KCYC	
TOTAL:						
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
23945	CONTINUITY	IN VERIFICATION	NA			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2108 AUG '99 MONITOR,D.P-ANAM,PI.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2108	B7	9922	DK913650AAF	24	SOIC	300	Anam, PI (ATP)
PROCESS Single Poly, Single Metal 5.0 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24386	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
		TOTAL:	635	FAIL RATE (Fits): 1.44E+06		0
24384	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	238	144	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
24388	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2109S JUN '99 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2109	A7	9839	DM811523AAA	28	SOIC	300	Carsem
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24040	INFANT LIFE	125C, 7.0 VOLTS	233	48	HOUR	0
24327	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
TOTAL:			71	DEVICE HRS: 1.29E+07		0
23947	ULTRASOUND	J-STD-020	4	2	DAYS	0
TOTAL:						0
23948	STORAGE LIFE	125C	237	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	237	168	HOUR	0
	CONVECTION REFLOW	235C	237	195	PASS	0
TOTAL:						0
24039	PRECONDITION U/S	J-STD-020	0	2	DAYS	0
TOTAL:						0
24328	TEMP CYCLE	-55C TO 125C	50	300	CYCL	0
TOTAL:						0
24329	HAST	130C, 85%R.H.,5.5V	66	100	HOUR	0
TOTAL:						0
24330	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2109S MAR '99 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2109	A7	9839	DM812688AAA	28	SOIC	300	Carsem
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: Tuse:
Ea: Vuse:
β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23723	INFANT LIFE	125C, 7.0 VOLTS	228	48	HOUR	5
23832	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	74	1000	HOUR	3
TOTAL:			FAIL RATE (Fits): 314	DEVICE HRS: 3.00E+07		8
23363	ULTRASOUND	J-STD-020	0	1	DAYS	
TOTAL:						
23364	STORAGE LIFE	125C	237	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	237	192	HOUR	
	CONVECTION REFLOW	235C	237	195	PASS	0
TOTAL:						
23722	PRECONDITION U/S	J-STD-020	0	1	DAYS	
TOTAL:						
23833	TEMP CYCLE	-55C TO 125C	50	300	CYCL	0
			50	1000	CYCL	0
TOTAL:						
23834	HAST	130C, 85%R.H.,5.5V	66	100	HOUR	0
TOTAL:						
23835	AUTOCLAVE	121C STEAM, UNBIASED	31	96	HOUR	4

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2109S MAR '99 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2109	A7	9839	DM812688AAA	28	SOIC	300	Carsem
PROCESS Single Poly, Single Metal 0.8 μ m Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β :	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						4
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
23723	GND_SENSE	IN PROCESS (4 UNITS)	IN PROCESS			
23723	TERM RESIST	IN PROCESS (1 UNIT)	IN PROCESS			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2118M JUN '99 MONITOR,D.P. ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2118M	A4	9912	DN848138AAA	36	SSOP	300	Anam, K (ASI)
PROCESS Single Poly, Double Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: Tuse:
Ea: Vuse:
β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24038	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
24070	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	76	336	HOUR	1
TOTAL:			428	FAIL RATE (Fits): DEVICE HRS: 4.72E+06		1
23949	ULTRASOUND	J-STD-020	0	2	DAYS	
TOTAL:						
23950	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	238	264	HOUR	
	CONVECTION REFLOW	235C	238	267	PASS	0
TOTAL:						0
24037	PRECONDITION U/S	J-STD-020	0	2	DAYS	
TOTAL:						
24071	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
24072	HAST	130C, 85%R.H.,5.5V	77	100	HOUR	0
TOTAL:						0
24073	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2118M JUN '99 MONITOR,D.P. ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2118M	A4	9912	DN848138AAA	36	SSOP	300	Anam, K (ASI)
PROCESS Single Poly, Double Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24070	CONTINUITY	IN VERIFICATION (2 UNITS)	NA			
24070	RDM-HD	IN VERIFICATION (2 UNITS)	NA			
24070	RDM-HD	IN VERIFICATION (1 UNIT)	NA			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2118M SEP '99 MONITOR, D.P. Carsem

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2118M	A4	9919	DM905555AAD	36	SSOP	300	Carsem
PROCESS Single Poly, Double Metal 0.8 µm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24453	INFANT LIFE	125C, 6.0 VOLTS	231	48	HOUR	0
		TOTAL:	643	DEVICE HRS: 1.42E+06		0
24451	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	238	240	HOUR	
	CONVECTION REFLOW	235C	236	3	PASS	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2165Q OCT '98 MONITOR - ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2165	B1	9837	DN811583AAB	28	LCC	450	Anam, K (ASI)
PROCESS Single Poly, Single Metal 1.2 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23171	AUTOCLAVE	121C STEAM, UNBIASED	38	96	HOUR	0
TOTAL:						0

JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION
23168	SHORT XOUT	IN VERIFICATION	NA

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2180A APR '99 MONITOR - ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2180A	B3	9850	DN839402AAC	44	LCC	650	Anam, K (ASI)
PROCESS Single Poly, Single Metal 2.0 μm Pfield							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23775	INFANT LIFE	125C, 7.0 VOLTS	235	48	HOUR	0
23879	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
TOTAL:			30	DEVICE HRS: 3.08E+07		0
23667	ULTRASOUND	J-STD-020	0	1	DAYS	
TOTAL:						
23668	TEMP CYCLE	-55C TO 125C	241	10	CYCL	
	STORAGE LIFE	125C	241	34	HOUR	
	MOISTURE SOAK	30C/60% R.H.	241	178	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	181	PASS	0
TOTAL:						0
23774	PRECONDITION U/S	J-STD-020	0	2	DAYS	
TOTAL:						
23880	TEMP CYCLE	-55C TO 125C	60	300	CYCL	0
			60	1000	CYCL	0
TOTAL:						0
23881	HAST	130C, 85%R.H.,5.5V	60	100	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2180A APR '99 MONITOR - ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2180A	B3	9850	DN839402AAC	44	LCC	650	Anam, K (ASI)
PROCESS Single Poly, Single Metal 2.0 μm Pfield							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23882	AUTOCLAVE	121C STEAM, UNBIASED	37	96	HOUR	1
TOTAL:						1

JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION
23882	VECTOR	IN PROCESS	IN PROCESS

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2401 JUN '99 TO92 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2401	C2	9910	DM840523AHA	3	TO92	180	Carsem
PROCESS Single Poly, Single Metal 0.6 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: Tuse:
Ea: Vuse:
β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23956	INFANT LIFE	125C, 6.0 VOLTS	231	48	HOUR	3
24411	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
TOTAL:			879	FAIL RATE (Fits): DEVICE HRS: 4.75E+06		3
24412	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
24413	HAST	130C, 85%R.H.,5.5V	74	100	HOUR	0
TOTAL:						0
24414	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION
23956	PREFUNCTIONAL	IN VERIFICATION (2 UNITS)	NA
23956	DQ RESISTANCE	IN VERIFICATION (1 UNIT)	NA

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2401 SEP '99 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2401	C2	9926	DM912460AAA	3	TO92	180	Carsem
PROCESS Single Poly, Single Metal 0.6 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24472	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
24473	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
TOTAL:			192	FAIL RATE (Fits): DEVICE HRS: 4.77E+06		0
24474	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
TOTAL:						0
24476	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2434 NOV '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2434	D1	9827	DM809170AAA	3	TO226 (PR35)	350	Carsem
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
22801	INFANT LIFE	125C, 7.0 VOLTS	237	48	HOUR	0
22857	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	DEVICE HRS: 3.09E+07		0
22858	TEMP CYCLE	-55C TO 125C	50	300	CYCL	0
			50	1000	CYCL	0
		TOTAL:				0
22859	HAST	120C, 85%R.H.,5.5V	70	100	HOUR	0
		TOTAL:				0
22860	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2434 FEB '99 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2434	D1	9828	DM809174AAB	3	TO226 (PR35)	350	Carsem
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23278	INFANT LIFE	125C, 7.0 VOLTS	237	48	HOUR	0
24066	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	76	336	HOUR	0
		125C, 7.0 VOLTS	76	1000	HOUR	0
TOTAL:			30	DEVICE HRS: 3.05E+07		0
24067	TEMP CYCLE	-55C TO 125C	50	300	CYCL	0
			50	1000	CYCL	0
TOTAL:						0
24068	HAST	130C, 85%R.H.,5.5V	70	100	HOUR	0
TOTAL:						0
24069	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2434 AUG '99 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2434	D1	9837	DM811482AAA	3	TO226 (PR35)	350	Carsem
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24391	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
24392	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
TOTAL:			71	DEVICE HRS: 1.30E+07		0
24393	TEMP CYCLE	-55C TO 125C	50	300	CYCL	0
TOTAL:						0
24395	AUTOCLAVE	121C STEAM, UNBIASED	37	96	HOUR	0
TOTAL:						

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2502 MAR '99 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C2	9913	DM842206ALB	8	SOIC	150	Carsem S
PROCESS Double Poly, Single Metal 0.6 μm EPROM process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: Tuse:
Ea: Vuse:
β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24153	INFANT LIFE	125C, 6.0 VOLTS	222	48	HOUR	0
24261	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
TOTAL:			81	DEVICE HRS: 1.13E+07		0
23635	ULTRASOUND	J-STD-020	0	0	DAYS	
TOTAL:						
23636	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	VAPOR PHASE REFLOW	217C	238	3	PASS	
TOTAL:						
24152	PRECONDITION U/S	J-STD-020	0	1	DAYS	
TOTAL:						
24262	TEMP CYCLE	-55C TO 125C	34	300	CYCL	0
			34	1000	CYCL	0
TOTAL:						0
24263	BIASED MOISTURE	85/85, 5.5 VOLTS	76	274	HOUR	0
TOTAL:						0
24264	STORAGE LIFE	150C	34	336	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2502 MAR '99 MONITOR-CARSEM							
DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C2	9913	DM842206ALB	8	SOIC	150	Carsem S
PROCESS Double Poly, Single Metal 0.6 μm EPROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
			34	1000	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stess

RELIABILITY MONITOR

DS2502 JUN '99 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C2	9915	DM846764AAA	8	SOIC	150	Carsem S
PROCESS Double Poly, Single Metal 0.6 μm EPROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24169	INFANT LIFE	125C, 6.0 VOLTS	229	48	HOUR	0
24174	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	
		TOTAL:			FAIL RATE (Fits):	81
					DEVICE HRS:	1.13E+07
			0			0
23957	ULTRASOUND	J-STD-020	0	2	DAYS	
		TOTAL:				
23958	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	VAPOR PHASE REFLOW	217C	238	3	PASS	
		TOTAL:				
24175	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24176	BIASED MOISTURE	85/85, 5.5 VOLTS	75	274	HOUR	0
		TOTAL:				0
24177	STORAGE LIFE	150C	37	336	HOUR	0
			37	1000	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2502 SEP '99 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C2	9918	DM849359ACA	8	SOIC	150	Carsem S
PROCESS Double Poly, Single Metal 0.6 μm EPROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24480	INFANT LIFE	125C, 6.0 VOLTS	231	48	HOUR	0
TOTAL:			FAIL RATE (Fits): 643	DEVICE HRS: 1.42E+06		0
24478	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	236	3	PASS	1
TOTAL:						1

Empty "No of Fails" TOTAL implies that Material is still in stess

RELIABILITY MONITOR

DS5002 APR '99 MONITOR,D.P.-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	B3	9905	DM831680AAC	80	PQFP	550	Carsem
PROCESS Single Poly, Single Metal 1.2 μm Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23852	INFANT LIFE	125C, 7.0 VOLTS	199	48	HOUR	0
23973	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
TOTAL:			30	DEVICE HRS: 3.02E+07		0
23671	ULTRASOUND	J-STD-020	0	1	DAYS	
TOTAL:						
23672	STORAGE LIFE	125C	203	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	203	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	203	171	PASS	0
TOTAL:						0
23851	PRECONDITION U/S	J-STD-020	0	2	DAYS	
TOTAL:						
23974	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
23975	BIASED MOISTURE	85/85, 5.5 VOLTS	42	274	HOUR	0
			42	959	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS5002 APR '99 MONITOR,D.P.-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	B3	9905	DM831680AAC	80	PQFP	550	Carsem
PROCESS Single Poly, Single Metal 1.2 μ m Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β :	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23976	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stess

RELIABILITY MONITOR

DS87520 NOV '98 MONITOR,D.P.- ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS87C520	A13	9832	DN821500AAB	44	LCC	650	Anam, K (ASI)
PROCESS Double Poly, Single Metal 0.8 μm EPROM w/silicided poly(s)							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23309	INFANT LIFE	125C, 7.0 VOLTS	236	48	HOUR	0
23593	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	76	1000	HOUR	0
TOTAL:			30	DEVICE HRS: 3.06E+07		0
22843	ULTRASOUND	J-STD-020	4	1	DAYS	0
TOTAL:						0
22844	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	241	264	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	240	267	PASS	0
TOTAL:						0
23308	PRECONDITION U/S	J-STD-020	4	1	DAYS	0
TOTAL:						0
23594	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
23595	HAST	130C, 85%R.H.,5.5V	59	100	HOUR	0
TOTAL:						0
23596	STORAGE LIFE	150C	59	336	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS87520 NOV '98 MONITOR,D.P.- ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS87C520	A13	9832	DN821500AAB	44	LCC	650	Anam, K (ASI)
PROCESS Double Poly, Single Metal 0.8 μm EPROM w/silicided poly(s)							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
			58	1000	HOUR	1
TOTAL:						1

JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION
23596	OP40	PROCESS/DESIGN INTERACTION	REV 15 WAS RELEASED TO CORRECT THIS PROBLEM

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS80320 APR '99 MONITOR,ANAM-PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80C320	C4	9903	DK826547AAD	40	DIP	600	Anam, PI (ATP)
PROCESS Single Poly, Single Metal 0.6 μm Poly 1 Silicide							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23673	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
23690	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
TOTAL:			30	DEVICE HRS: 3.08E+07		0
23691	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
23692	BIASED MOISTURE	85/85, 5.5 VOLTS	72	274	HOUR	0
			72	959	HOUR	0
TOTAL:						0
23693	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS87520 FEB '99 MONITOR,D.P.-ANAM,K

DEVICE	REVISION	DATE CODE	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS87C520	A11	9838	DN825394AAB	44	LCC	650	Anam, K (ASI)

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23306	ULTRASOUND	J-STD-020	4	1	DAYS	0
		TOTAL:				0
23307	STORAGE LIFE	125C	239	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	239	240	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	239	3	PASS	0
		TOTAL:				0
23414	PRECONDITION U/S	J-STD-020	4	1	DAYS	0
		TOTAL:				0
23854	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
		-55C TO 125C	40	1000	CYCL	0
		TOTAL:				0
23855	HAST	130C, 85%R.H.,5.5V	59	100	HOUR	0
		TOTAL:				0
23856	STORAGE LIFE	150C	59	336	HOUR	0
		150C	58	1000	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress